

Search Notes

Application/Control No.

10/602,810

Examiner

/BINH K. TIEU/

Applicant(s)/Patent under
Reexamination

AN

Art Unit

2614

SEARCHED

| Class | Subclass | Date | Examiner |
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| 455 | 410-411 | 8/5/2007 | BKT |
| ↓ | 414.1 | ↓ | ↓ |
| ↓ | 557 | ↓ | ↓ |
| ↓ | 566 | ↓ | ↓ |
| ↓ | 550.1 | ↓ | ↓ |
| ↓ | 412.2 | ↓ | ↓ |
| ↓ | 418-420 | ↓ | ↓ |
| 726 | 11 | ↓ | ↓ |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|-----------------------|----------|------|
| WEST DATABASES SEARCH | 8/5/2007 | BKT |
| WEST DATABASES SEARCH | 8/6/2007 | BKT |
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